


<b>Search Notes</b>  	<b>Application/Control No.</b>  10066109	<b>Applicant(s)/Patent Under Reexamination</b>  MCNEIL, DANIEL D.
	<b>Examiner</b>  Pardo, Thuy N	<b>Art Unit</b>  2165

SEARCHED			
Class	Subclass	Date	Examiner
707	101, 102, 103x, 104.1, 204	7/21/2007	TP
714	6	7/21/2007	TP

SEARCH NOTES		
Search Notes	Date	Examiner
WEST, IEEE	7/21/2007	TP

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
707	101, 102, 103x, 104.1	7/21/2007	TP
714	6	7/21/2007	TP